



Electronic Components Division (ECD)

Motion Control Products

Change Notification

Notification Date : Nov 2001

Re: HEDS-97XX (include all options) and specials

Please be notified that Agilent Technologies is making the following product change(s) on the effective date noted for the products listed below. Satisfactory reliability data will be gathered and recorded to assure continuance of the high quality standards as set forth in our standard catalog parts.

Agilent Technologies Base Part Numbers Affected:

| Part Numbers |
|---|
| HEDS-97XX (Include all options) |
| In addition, all specials based on this base parts are also affected |

Description of Change:

Agilent Technologies is qualifying new emitter Fab location for the following purposes

Consolidation of wafer fab location.

Reason for Change:

Change wafer fabrication location from US to Singapore

Implementation:

The implementation of this change is expected to be December 2001

Qualification/Reliability Data:

The qualification completed in September 2001

Customer samples will be available on September 2001 and will be provided upon a request basis.

HEDS-97XX Reliability Qualification Results

| TEST | | 100 | 500* | 1000 |
|-------|---------|-------|-------|-------|
| TMCL | Control | 0/200 | 0/200 | 0/200 |
| | Eval | 0/600 | 0/600 | 0/600 |
| TEST | | 168 | 500* | 1000 |
| HTOL | Control | 0/52 | 0/52 | 0/52 |
| | Eval | 0/156 | 0/156 | 0/156 |
| WHTOL | Control | 0/52 | 0/52 | 0/52 |
| | Eval | 0/156 | 0/156 | 0/156 |

Note : * denotes release points

1. **TMCL** - Temperature Cycling -40°C/100°C with 15 mins transfer and 5 mins dwell time. It is good for testing the wire bonding tensile strength and detecting wire bonding problems, delamination and component cracking problem.

2. **HTOL** - High Temperature Operating Life test, performed at 100°C with bias i.e 5V on V_c and meant for checking the device performance when operated at thermal and electrical condition.

3. **WHTOL** - Wet Hot Temperature Operating Life test, performed at 85°C/85% humidity with bias i.e. 5V on V_{cc} and meant for checking the device resistance at high temperature, high humidity and electrical stress condition. It is good to check for the product susceptibility to delamination.

Conclusion :

Completed 1000 hours Reliability Test without any failure, thus the HEDS-97XX family is qualified for Product build and released sample for Customer Qualification build.